## **AMENDMENTS TO CLAIMS**

## Amend the claims as follows:

- 1. (Currently Amended) A magnetic localization device, comprising:
- a) a field generator for generating a magnetic field;
- b) a field sensor for measuring the magnetic field;
- c) a reference sensor for measuring the magnetic field at a known reference position; and
- d) a control unit, which is arranged for determining the <u>a</u> position of the field sensor relative to the field generator and thereby for compensating <u>for</u> external field distortions by taking the reference sensor into consideration <u>and correcting the determined position of the field sensor if external field distortions are present.</u>
- 2. (Previously Presented) A localization device as claimed in claim 1, wherein the spatial position of the field generator is known.
- 3. (Currently Amended) A localization device as claimed in claim 1, wherein at least one of the field generator and [[/or]] the reference sensor [[are]] is fastened to the gantry of a computer tomograph.
- 4. (Currently Amended) A localization device as claimed in claim 1, wherein the control unit contains a memory with a calibration function, which provides a correction shift for [[the]] an uncorrected determined position of the field sensor based on measured signals of the reference sensor and the field sensor.
- 5. (Canceled)

- 6. (Currently Amended) A method for position measurement with a magnetic localization device, comprising the steps of:
- a) collecting the signals of at least one of a field sensor and [[/or]] a field generator;
- b) collecting the signals of a magnetic reference sensor, which is placed at a known spatial position relative to the field generator or to the field sensor; and
- c) determining the <u>a</u> position of the field sensor relative to the field generator, where external field distortions are compensated <u>for</u> by taking the signals of the reference sensor into consideration <u>and correcting the determined position of the field sensor if external field distortions are present.</u>
- 7. (Currently Amended) A method as claimed in claim 6, wherein a correction function is determined, which indicates a correction shift for [[the]] an uncorrected determined position of the field sensor in dependence on the signal of the reference sensor and the uncorrected determined position of the field sensor.
- 8. (Currently Amended) A method as claimed in claim 7, for position measurement with a magnetic localization device, comprising the steps of:
- a) collecting the signals of at least one of a field sensor and a field generator;
- b) collecting the signals of a magnetic reference sensor, which is placed at a known spatial position relative to the field generator or to the field sensor;
- determining the position of the field sensor relative to the field generator, where external field distortions are compensated for by taking the signals of the reference sensor into consideration;
- d) wherein a correction function is determined, which indicates a correction shift for an uncorrected determined position of the field sensor in dependence on the signal of the reference sensor and the uncorrected determined position of the field sensor; and

- e) wherein the correction function for support points in a volume of interest is empirically determined and extended by extrapolation or interpolation respectively on the whole volume.
- 9. (Previously Presented) A method as claimed in claim 6, wherein a parameter is determined from the signal of the reference sensor, which parameter characterizes the external field distortion.
- 10. (Currently Amended) A method as claimed in claim 9, for position measurement with a magnetic localization device, comprising the steps of:
- a) collecting the signals of at least one of a field sensor and a field generator;
- b) collecting the signals of a magnetic reference sensor, which is placed at a known spatial position relative to the field generator or to the field sensor;
- c) determining the position of the field sensor relative to the field generator, where external field distortions are compensated for by taking the signals of the reference sensor into consideration;
- d) wherein a parameter is determined from the signal of the reference sensor, which parameter characterizes the external field distortion; and
- e) wherein the parameter describes the angle of rotation of a computer tomograph situated in the vicinity of the localization device.
- 11. (New) A method as claimed in claim 7, wherein the correction shift further depends on empirical measurements taken with a probe sensor at one or more support points in a volume of interest.
- 12. (New) A method as claimed in claim 7, wherein the signal of the reference sensor is used to determine a correction parameter describing an angle of rotation of a computer tomograph situated in the vicinity of the localization device.

- 13. (New) A localization device as claimed in claim 4, wherein the correction shift is further based on empirical measurements taken with a probe sensor at one or more support points in a volume of interest.
- 14. (New) A localization device as claimed in claim 4, wherein the measured signals of the reference sensor are used to determine a correction parameter describing an angle of rotation of a computer tomograph situated in the vicinity of the localization device.